

**Description**

The SX50N03D uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

**General Features**

$V_{DS}=30V$   $I_D=58A$

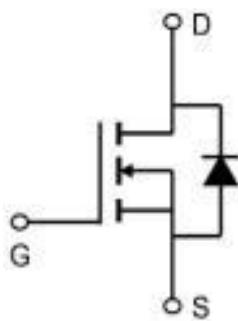
$R_{DS(ON)} < 10m\Omega$  @  $V_{GS}=10V$

**Application**

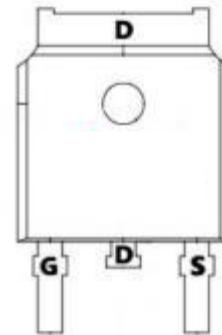
Battery protection

Load switch

Uninterruptible power supply



TO-252-3L

**Absolute Maximum Ratings ( $T_c=25^\circ C$  unless otherwise noted)**

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	30	V
$V_{GS}$	Gate-Source Voltage	$\pm 20$	V
$I_D@T_c=25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	58	A
$I_D@T_c=100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	30	A
$I_{DM}$	Pulsed Drain Current <sup>2</sup>	112	A
EAS	Single Pulse Avalanche Energy <sup>3</sup>	24.2	mJ
IAS	Avalanche Current	22	A
$P_D@T_c=25^\circ C$	Total Power Dissipation	37.5	W
TSTG	Storage Temperature Range	-55 to 175	°C
$T_J$	Operating Junction Temperature Range	-55 to 175	°C
$R_{eJA}$	Thermal Resistance Junction-Ambient <sup>1</sup>	62.5	°C/W
$R_{eJC}$	Thermal Resistance Junction-Case <sup>1</sup>	4	°C/W

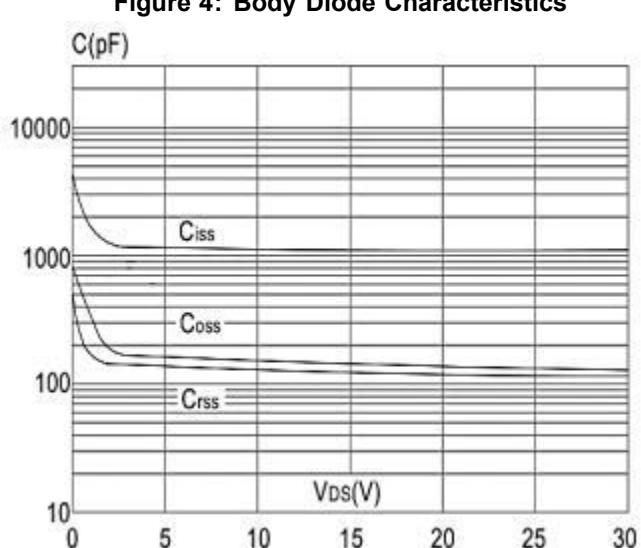
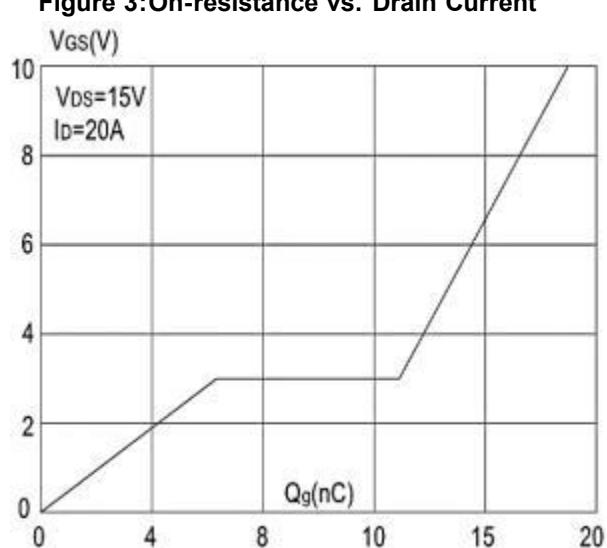
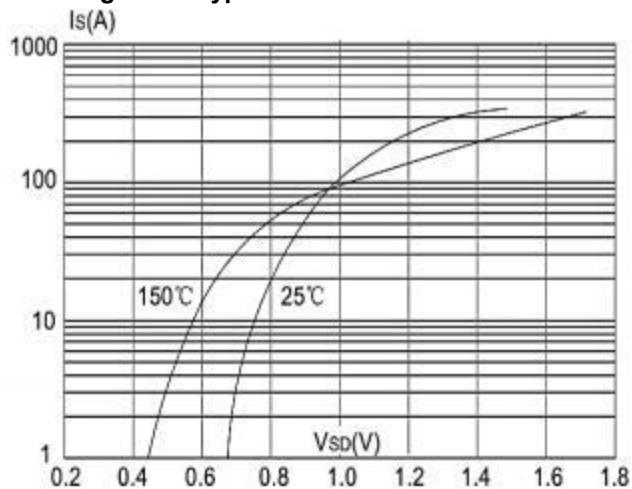
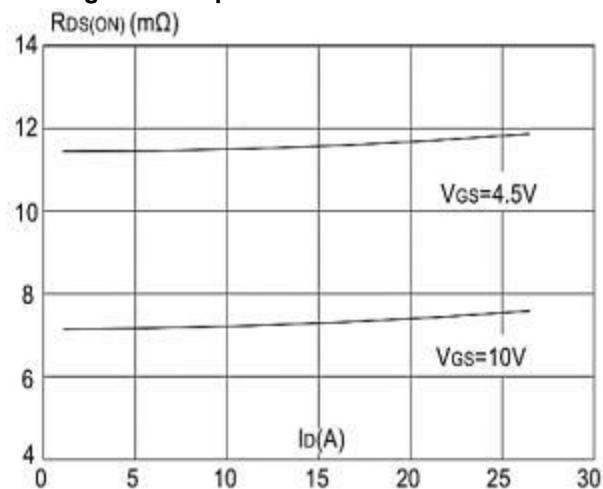
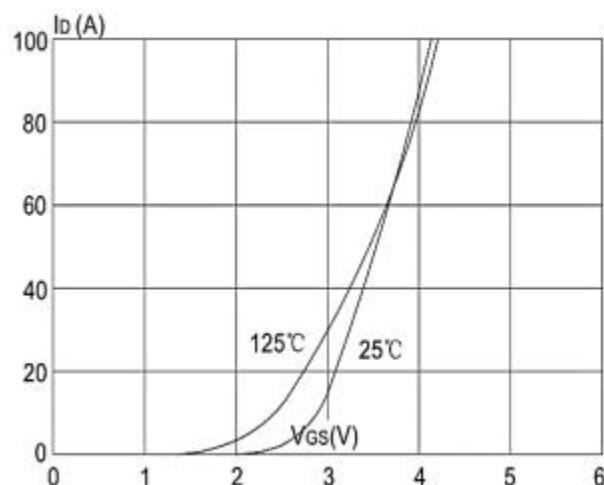
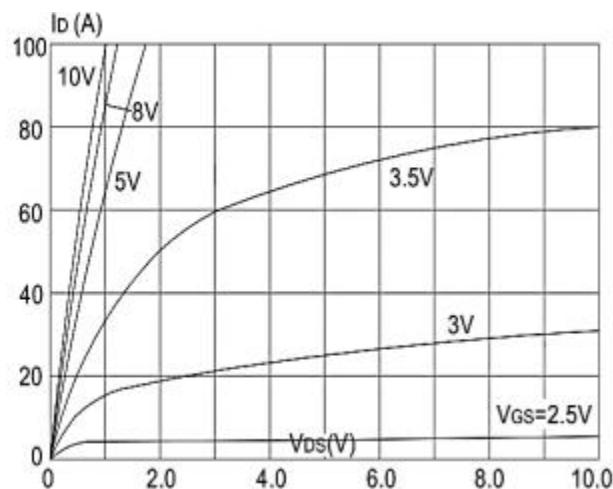
**Electrical Characteristics ( $T_J=25^\circ\text{C}$ , unless otherwise noted)**

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$ , $I_D=250\mu\text{A}$	30	33	---	V
$\Delta BVDSS/\Delta T_J$	BVDSS Temperature Coefficient	Reference to $25^\circ\text{C}$ , $I_D=1\text{mA}$	---	0.0193	---	$\text{V}/^\circ\text{C}$
RDS(ON)	Static Drain-Source On-Resistance <sup>2</sup>	$V_{GS}=10\text{V}$ , $I_D=30\text{A}$	---	7.5	10	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}$ , $I_D=15\text{A}$	---	11	16	
VGS(th)	Gate Threshold Voltage	$V_{GS}=V_{DS}$ , $I_D=250\mu\text{A}$	1.2	1.6	2.5	V
$\Delta V_{GS(\text{th})}$	$V_{GS(\text{th})}$ Temperature Coefficient		---	-3.97	---	$\text{mV}/^\circ\text{C}$
IDSS	Drain-Source Leakage Current	$V_{DS}=24\text{V}$ , $V_{GS}=0\text{V}$ , $T_J=25^\circ\text{C}$	---	---	1	$\text{uA}$
		$V_{DS}=24\text{V}$ , $V_{GS}=0\text{V}$ , $T_J=55^\circ\text{C}$	---	---	5	
IGSS	Gate-Source Leakage Current	$V_{GS}=\pm 20\text{V}$ , $V_{DS}=0\text{V}$	---	---	$\pm 100$	nA
gfs	Forward Transconductance	$V_{DS}=5\text{V}$ , $I_D=30\text{A}$	---	34	---	S
R <sub>g</sub>	Gate Resistance	$V_{DS}=0\text{V}$ , $V_{GS}=0\text{V}$ , $f=1\text{MHz}$	---	1.8	---	$\Omega$
Q <sub>g</sub>	Total Gate Charge (4.5V)	$V_{DS}=15\text{V}$ , $V_{GS}=4.5\text{V}$ , $I_D=15\text{A}$	---	9.8	---	nC
Q <sub>gs</sub>	Gate-Source Charge		---	4.2	---	
Q <sub>gd</sub>	Gate-Drain Charge		---	3.6	---	
Td(on)	Turn-On Delay Time	$V_{DD}=15\text{V}$ , $V_{GS}=10\text{V}$ , $R_G=3.3\text{k}\Omega$ , $I_D=15\text{A}$	---	4	---	ns
T <sub>r</sub>	Rise Time		---	8	---	
Td(off)	Turn-Off Delay Time		---	31	---	
T <sub>f</sub>	Fall Time		---	4	---	
C <sub>iss</sub>	Input Capacitance	$V_{DS}=15\text{V}$ , $V_{GS}=0\text{V}$ , $f=1\text{MHz}$	---	940	---	pF
C <sub>oss</sub>	Output Capacitance		---	131	---	
Crss	Reverse Transfer Capacitance		---	109	---	
I <sub>s</sub>	Continuous Source Current <sup>1,5</sup>	$V_G=V_D=0\text{V}$ , Force Current	---	---	43	A
ISM	Pulsed Source Current <sup>2,5</sup>		---	---	112	A
VSD	Diode Forward Voltage <sup>2</sup>	$V_{GS}=0\text{V}$ , $I_S=1\text{A}$ , $T_J=25^\circ\text{C}$	---	---	1	V
t <sub>rr</sub>	Reverse Recovery Time	IF=30A, $dI/dt=100\text{A}/\mu\text{s}$ , $T_J=25^\circ\text{C}$	---	8.5	---	nS
Q <sub>rr</sub>	Reverse Recovery Charge		---	2.2	---	nC

**Note :**

- 1、The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2、The data tested by pulsed, pulse width  $\leq 300\mu\text{s}$ , duty cycle  $\leq 2\%$
- 3、The EAS data shows Max. rating. The test condition is  $VDD=25\text{V}$ ,  $VGS=10\text{V}$ ,  $L=0.1\text{mH}$ ,  $IAS=28\text{A}$
- 4、The power dissipation is limited by  $175^\circ\text{C}$  junction temperature
- 5、The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.

### Typical Characteristics



## Typical Characteristics

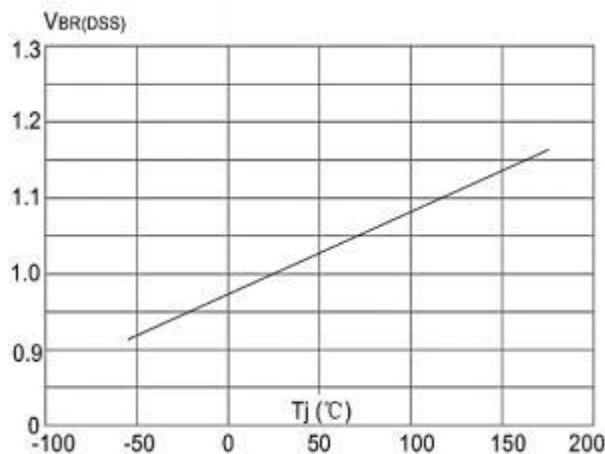


Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

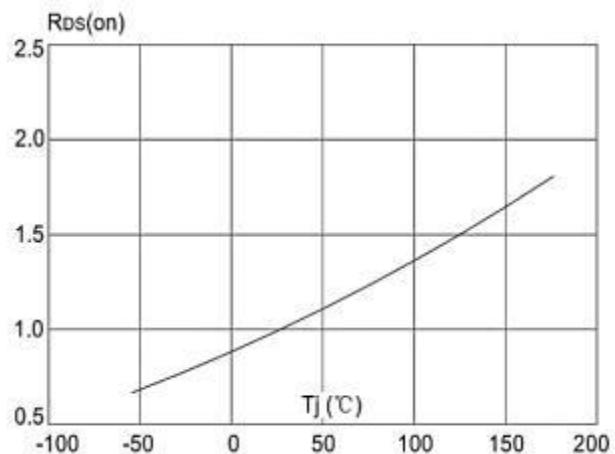


Figure 8: Normalized on Resistance vs. Junction Temperature

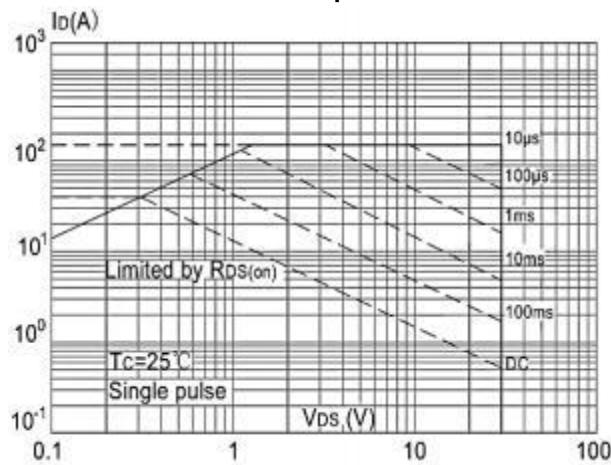


Figure 9: Maximum Safe Operating Area

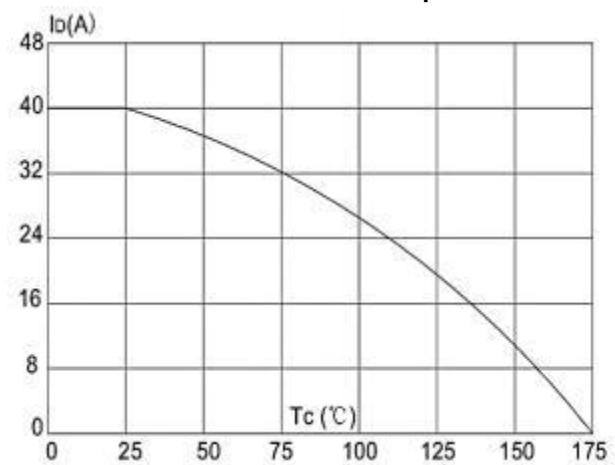


Figure 10: Maximum Continuous Drain Current vs. Ambient

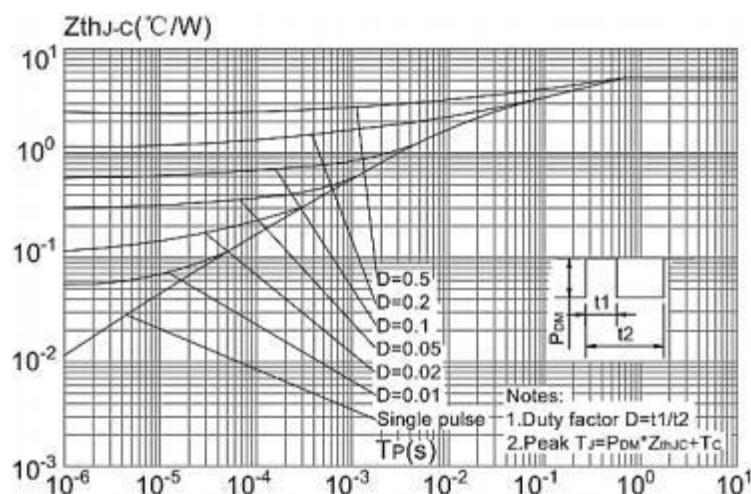
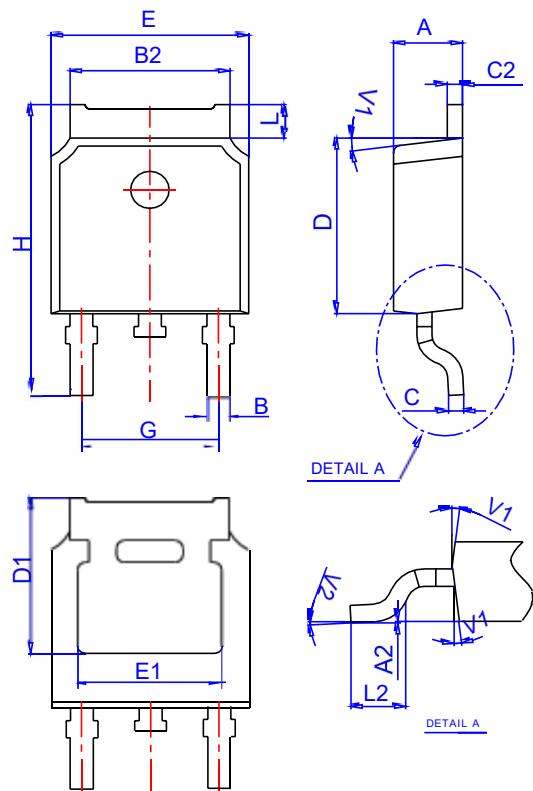


Figure 11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

## Package Mechanical Data: TO-252-3L



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	2.10		2.50	0.083		0.098
A2	0		0.10	0		0.004
B	0.66		0.86	0.026		0.034
B2	5.18		5.48	0.202		0.216
C	0.40		0.60	0.016		0.024
C2	0.44		0.58	0.017		0.023
D	5.90		6.30	0.232		0.248
D1	5.30REF			0.209REF		
E	6.40		6.80	0.252		0.268
E1	4.63			0.182		
G	4.47		4.67	0.176		0.184
H	9.50		10.70	0.374		0.421
L	1.09		1.21	0.043		0.048
L2	1.35		1.65	0.053		0.065
V1		7°			7°	
V2	0°		6°	0°		6°

### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
TAPING	TO-252-3L		2500